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1	BRS	L1	1079	ough adj transform\$5	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 13:49
2	BRS	L2	52	1 same graphic\$4	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:02
3	BRS	L3	52	2 and graphic\$4	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:04
4	BRS	L4	52	3 and ough adj transform\$5	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:12
5	BRS	L5	7	4 and vot\$3	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:17

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6	BRS	L6	1017	alpha adj blend\$3	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:17
7	BRS	L7	101	6 and accumulator\$1	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:18
8	BRS	L8	20	7 and observation	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:19
9	BRS	L9	2	8 and convol\$5	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:19
10	BRS	L10	2	9 and vot\$4	USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B	2004/04/02 14:20

	Type	L #	Hits	Search Text	DBs	Time Stamp
11	BRS	L11	3	<b>8 and hough adj transform\$5</b>	<b>USPAT; US-PGP UB; EPO; JPO; DERWE NT; IBM_TD B</b>	<b>2004/04/02 14:21</b>

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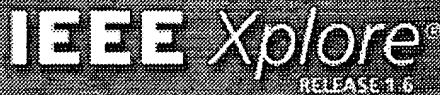
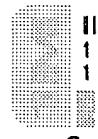
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